

June 18, 2014
Kyoto University
Informatics Seminar

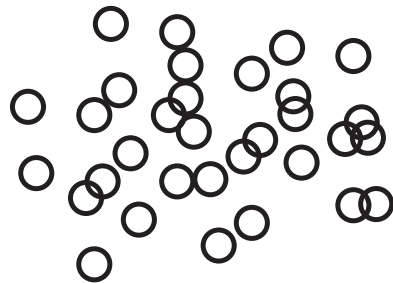


Distance-Based Outlier Detection via Sampling

ISIR, Osaka University
Mahito Sugiyama

Overview

- Today's topic is **outlier detection**
 - studied in statistics, machine learning & data mining (unsupervised learning)
- **Problem:**
How can we find outliers efficiently (from massive data) ?
- I will talk about recent advances in **distance-based** outlier detection methods



What is an Outlier (Anomaly) ?

- An outlier is “an observation which deviates so much from other observations as to arouse suspicions that it was generated by a different mechanism” (by Hawkins, 1980)
 - There is no fixed mathematical definition

What is an Outlier (Anomaly) ?

- An outlier is “an observation which deviates so much from other observations as to arouse suspicions that it was generated by a different mechanism” (by Hawkins, 1980)
 - There is no fixed mathematical definition
- Outliers appear everywhere:
 - Intrusions in network traffic
 - Credit card fraud
 - Defective products in industry
 - Medical diagnosis from X-ray images
- Outliers should be detected and removed
- Outliers can cause **fake results** in subsequent analysis

Distance-Based Outlier Detection

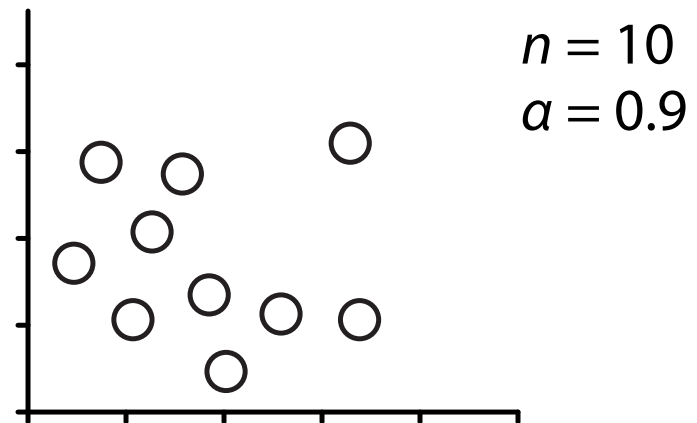
- Today I focus on the modern distance-based approach
 - A data point is an outlier, if its locality is sparsely populated [Aggrawal, 2013]
 - One of the most popular approaches in outlier detection
 - Distribution-free
 - Easily applicable for various types of data

Distance-Based Outlier Detection

- Today I focus on modern **distance-based** outlier detection
 - A data point is an outlier, if its locality is sparsely populated [Aggrawal, 2013]
 - One of the most popular approaches in outlier detection
 - Distribution-free
 - Easily applicable for various types of data
- See the following for other traditional model-based approaches, e.g., statistical tests or changes of variances
 - Aggarwal, C. C., Outlier Analysis, Springer (2013)
 - Kriegel, H.-P., Kröger, P., Zimak, A., Outlier Detection Techniques, Tutorial at SIGKDD2010 [\[Link\]](#)

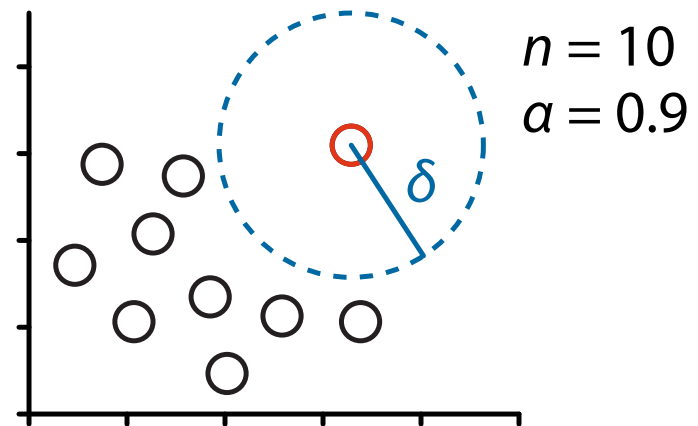
The First Distance-Based Method

- Knorr and Ng were the first to formalize a distance-based outlier detection scheme
 - “Algorithms for mining distance-based outliers in large datasets”, VLDB 1998
- Given a dataset X , an object $x \in X$ is a $DB(\alpha, \delta)$ -outlier if
$$|\{x' \in X \mid d(x, x') > \delta\}| \geq \alpha n$$
- $n = |X|$ (number of objects)
- $\alpha, \delta \in \mathbb{R}$ ($0 \leq \alpha \leq 1$) are parameters



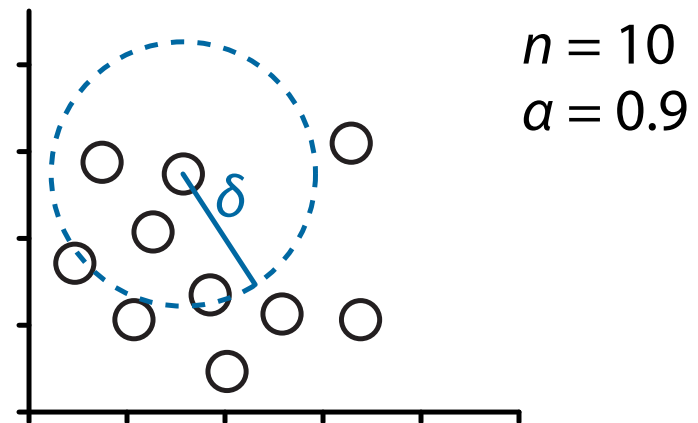
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From Classification to Ranking

- Two drawbacks of $DB(\alpha, \delta)$ -outliers
 1. Setting the distance threshold δ is difficult in practice
 - Setting α is not so difficult since it is always close to 1
 2. The lack of a ranking of outliers
- Ramaswamy *et al.* proposed to measure the outlierness by the *kth-nearest neighbor (kth-NN) distance*
 - Ramaswamy, S., Rastogi, R., Shim, K., “Efficient algorithms for mining outliers from large data sets”, SIGMOD 2000
 - The most basic distance-based approach to date

From Classification to Ranking

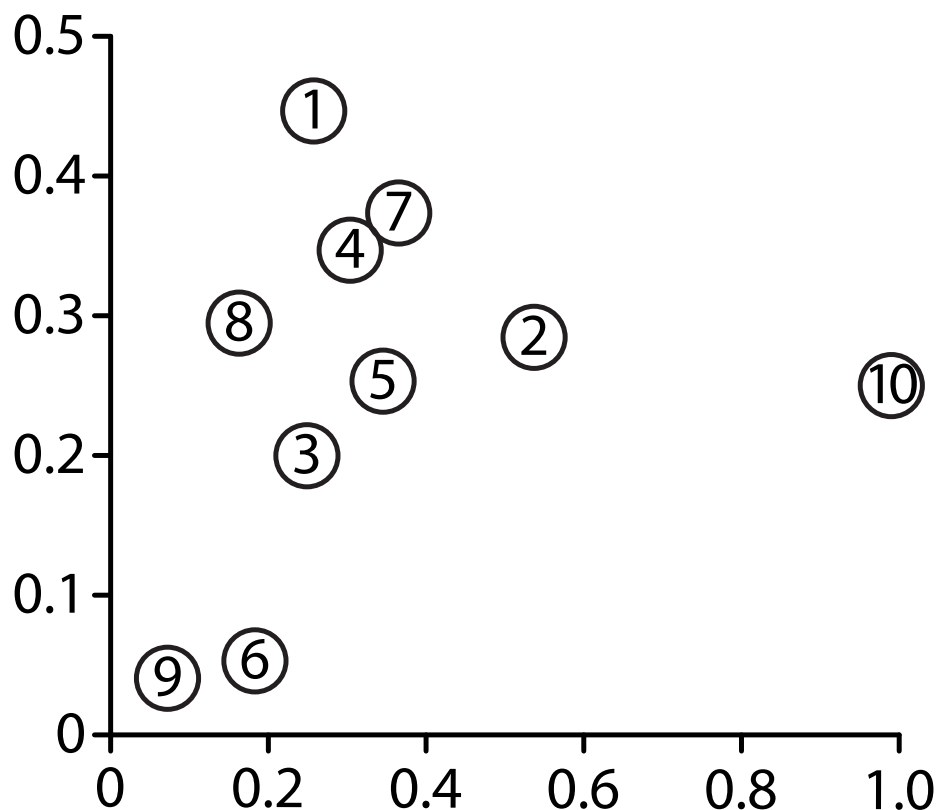
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 - The most basic distance-based approach to date
- ***From this study, the task of DB outlier detection becomes a ***ranking*** problem***
 - ***do not perform binary classification***

The k th-Nearest Neighbor Distance

- The k th-NN score $q_{k\text{thNN}}(x) := d^k(x; X)$
 - $d^k(x; X)$ is the distance between x and its k th-NN in X

The k th-Nearest Neighbor Distance

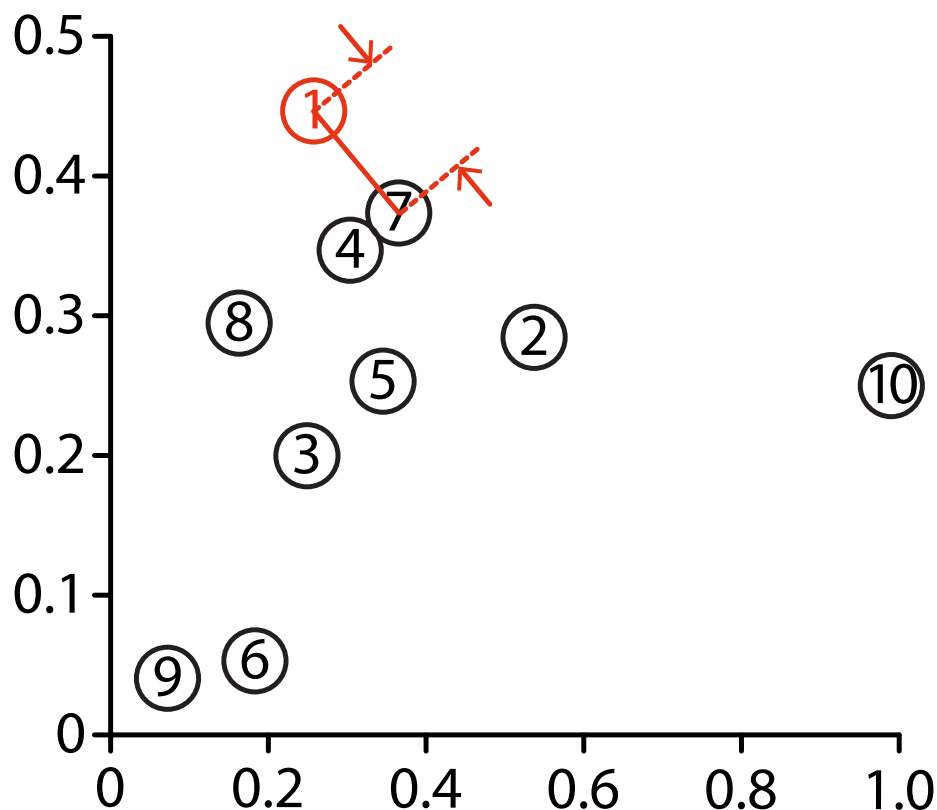
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id	score

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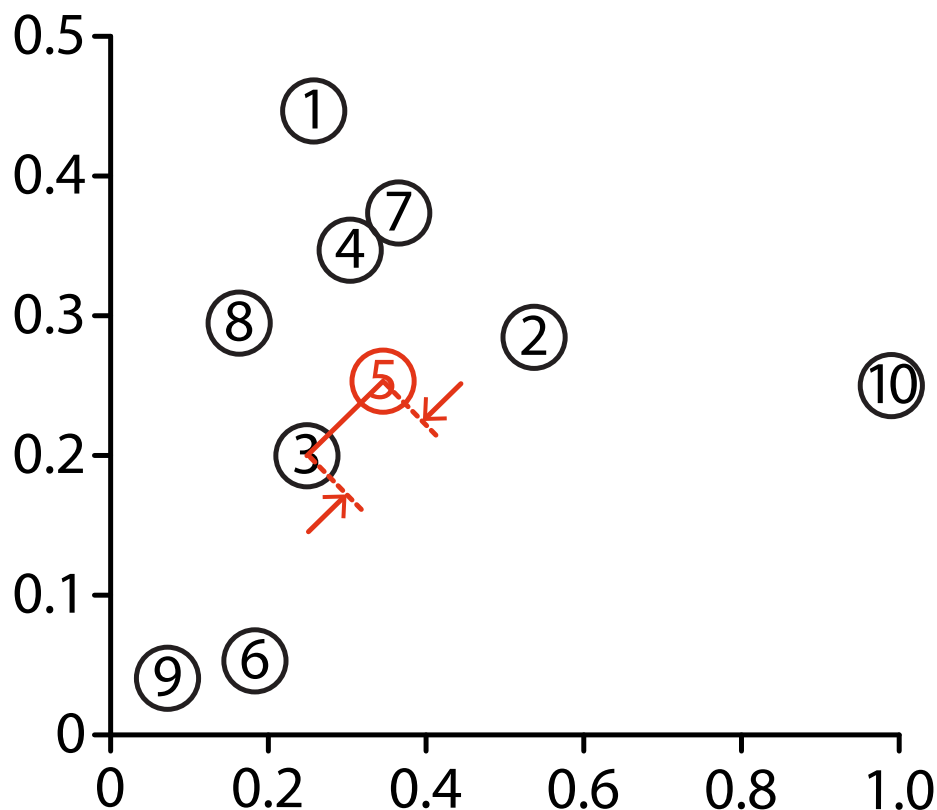
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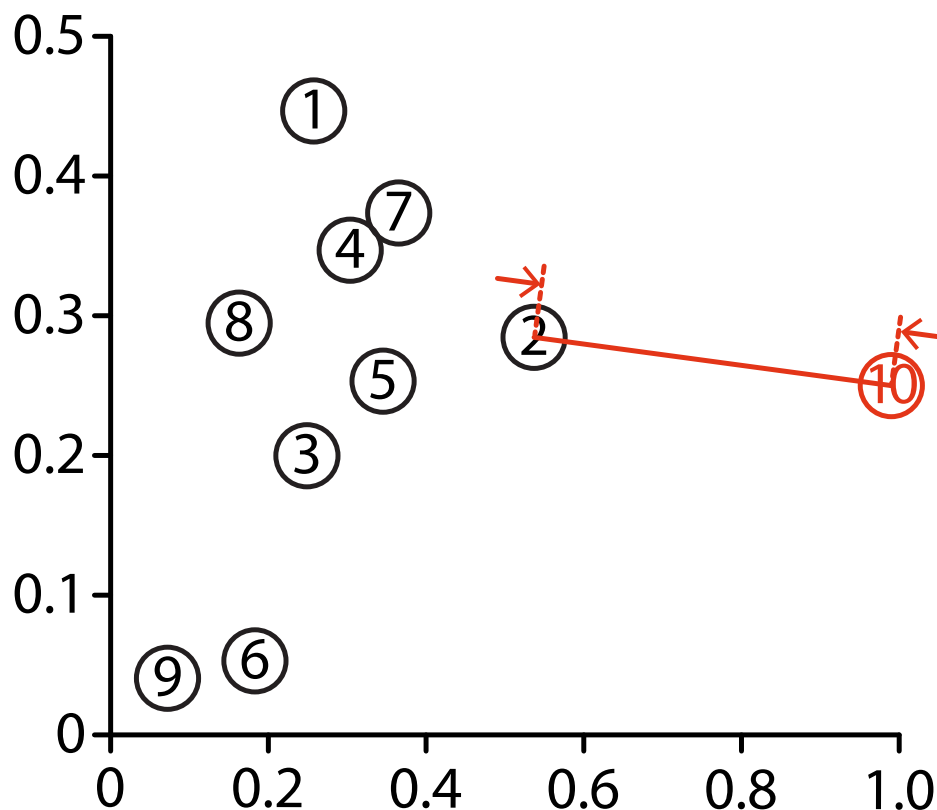
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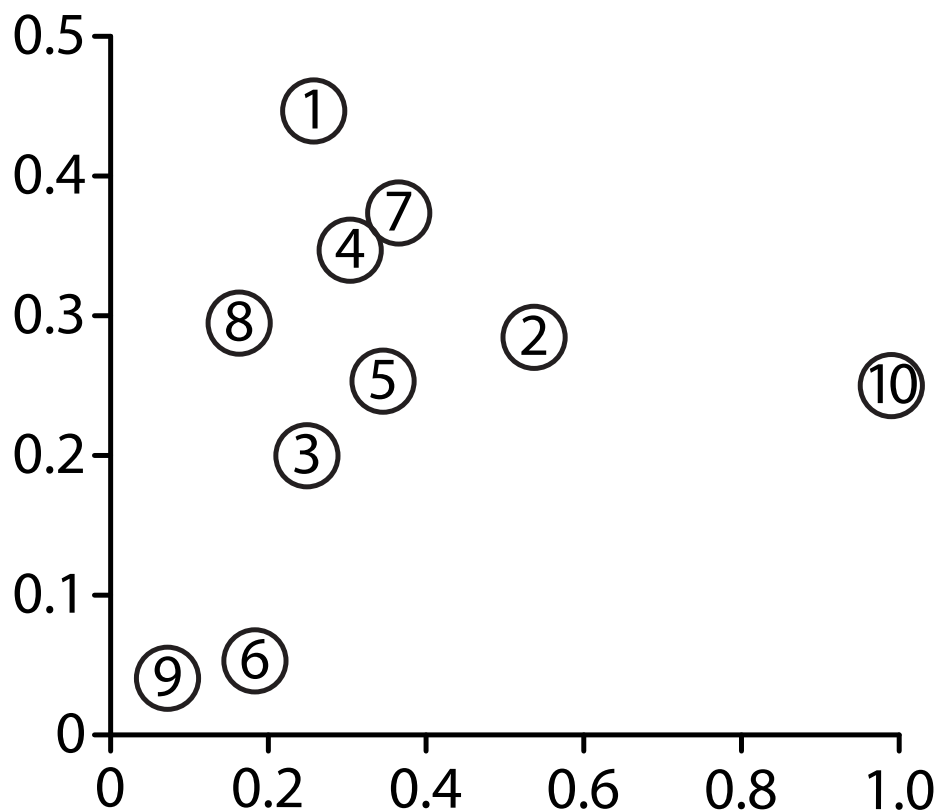
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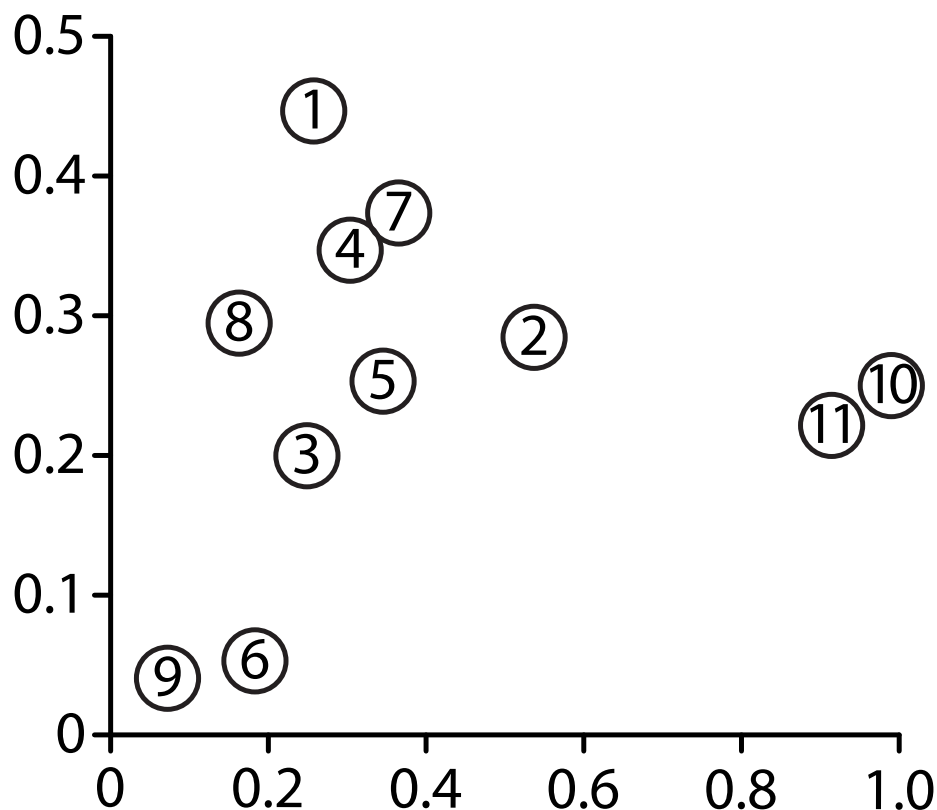
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3	0.110
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5	0.103
4	0.067
7	0.067

The k th-Nearest Neighbor Distance

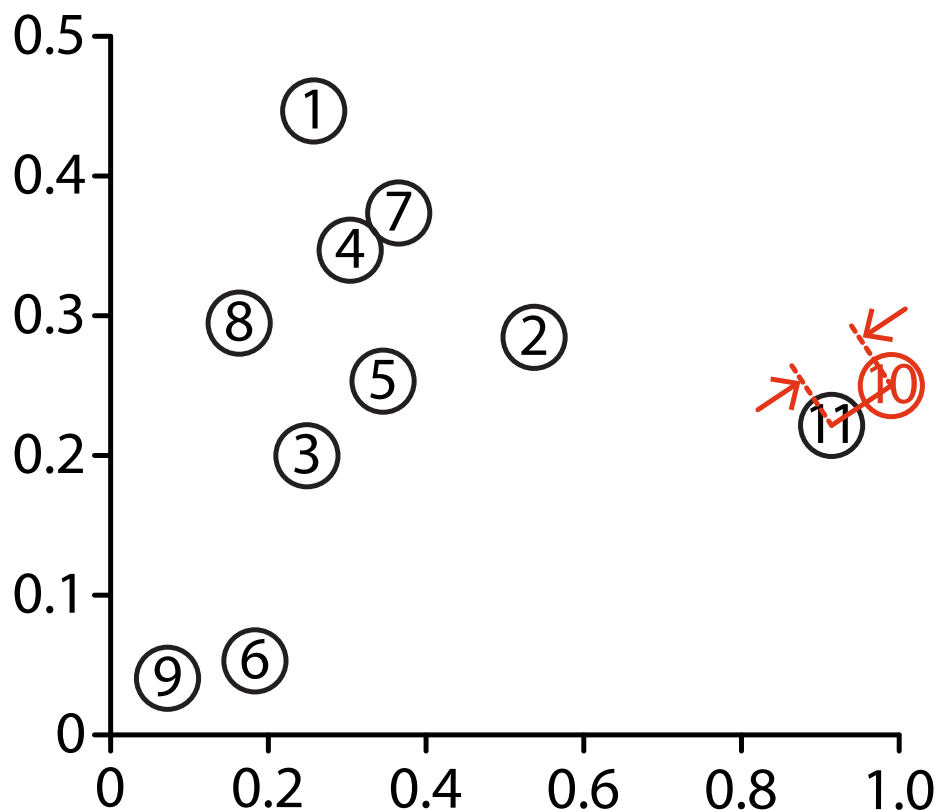
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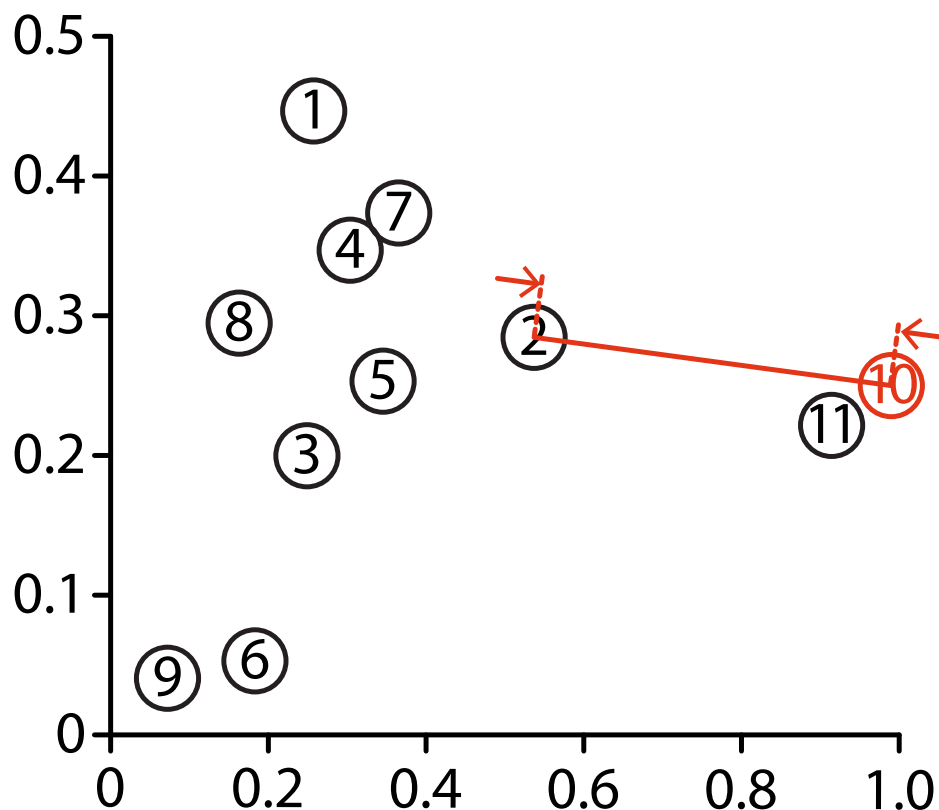
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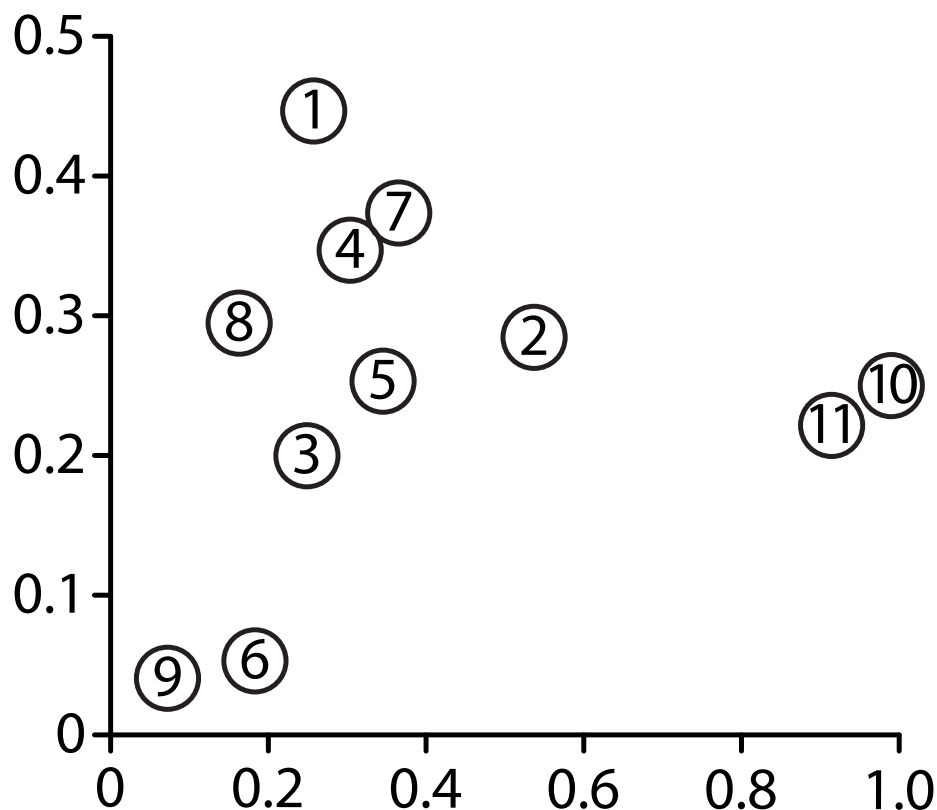
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id	score
10	0.454
11	0.436
9	0.238
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6	0.161
8	0.150
1	0.130
3	0.128
7	0.122
5	0.110
4	0.103

Connection with DB(α, δ)-Outliers

- The k th-NN score $q_{k\text{thNN}}(x) := d^k(x; X)$
 - $d^k(x; X)$ is the distance between x and its k th-NN in X
- Let $\alpha = (n - k)/n$
- For any threshold δ ,
the set of DB(α, δ)-outliers = $\{x \in X \mid q_{k\text{thNN}}(x) \geq \delta\}$

Two Drawbacks of the k th-NN Approach

1. Scalability; $O(n^2)$

- **Solution:** Partial computation of the pairwise distances to compute scores only for the top- κ outliers
 - ORCA [Bay & Schwabacher, SIGKDD 2003]
 - iORCA [Bhaduri et al., SIGKDD 2011]

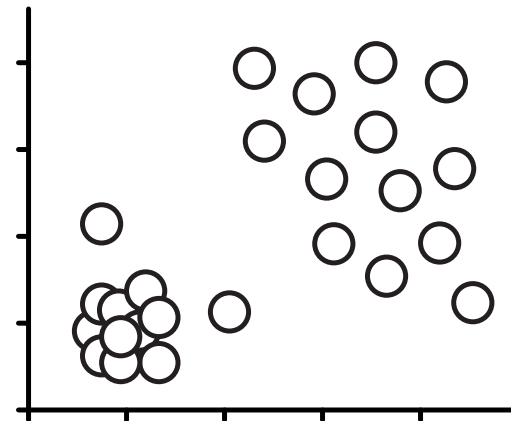
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2. Detection ability

- **Solution:** Introduce other definitions of the outlierness
 - Density-based (LOF)
[Breunig et al. SIGKDD 2000]
 - Angle-based (ABOD)
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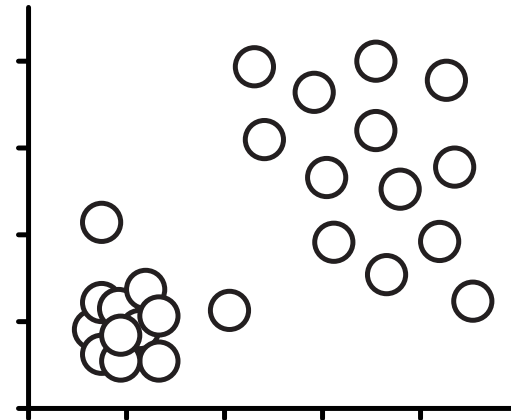
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Partial Computation for Efficiency

- The key technique in retrieving top- m outliers:
Approximate Nearest Neighbor Search (ANNS) principle
 - During computing $q_{k\text{thNN}}(x)$ within a **for** loop:
 $q_{k\text{thNN}}(x) = \infty$ ($k = 1$ for simplicity)
for each $x' \in X \setminus \{x\}$
 if $d(x, x') < q_{k\text{thNN}}(x)$
 $q_{k\text{thNN}}(x) = d(x, x')$
 end if
end for
the current value $q_{k\text{thNN}}(x)$ is monotonically decreasing
- In the **for** loop, if $q_{k\text{thNN}}(x)$ becomes smaller than the m th largest score so far, x never becomes an outlier
 - The **for** loop can be terminated earlier

Further Pruning with Indexing

- iORCA employed an indexing technique
 - Bhaduri, K., Matthews, B.L., Giannella, C.R., “Algorithms for speeding up distance-based outlier detection”, SIGKDD 2011
- Select a point $r \in X$ randomly
 - This r is a **reference point**
- Re-order the dataset X with increasing distance from r
- ***If $d(x, r) + q_{kthNN}(r) < c$, x never be an outlier***
 - c is the cutoff, the m -th largest score so far
- Drawback: the efficiency strongly depends on m

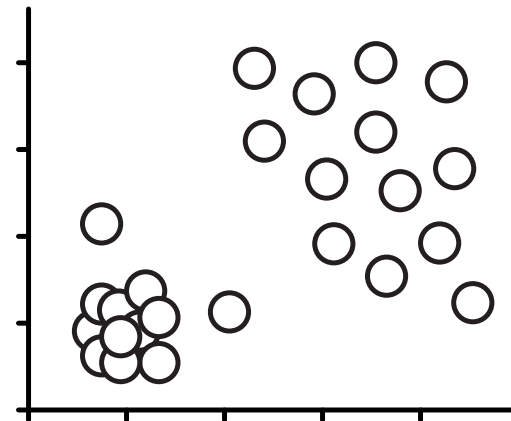
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LOF (Local Outlier Factor)

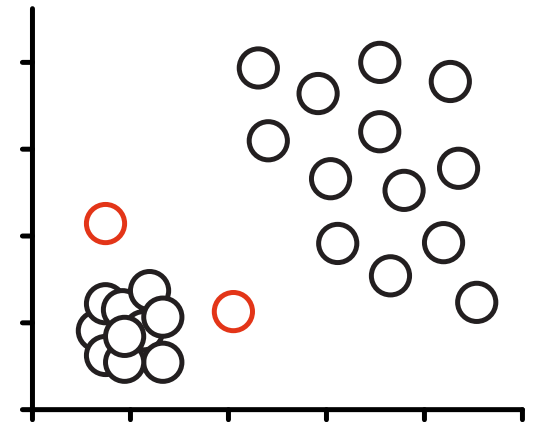
- $N^k(x)$: the set of k NNs of x
- The **reachability distance** $Rd(x; x') := \max \{ d^k(x', X), d(x, x') \}$
- The **local reachability density** is

$$\Delta(x) := \left(\frac{1}{|N^k(x)|} \sum_{x' \in N^k(x)} Rd(x; x') \right)^{-1}$$

- The **LOF** of x is defined as

$$LOF(x) := \frac{\left(1/|N^k(x)| \right) \sum_{y \in N^k(x)} \Delta(y)}{\Delta(x)}$$

- The ratio of the local reachability density of x and the average of the local reachability densities of its k NNs

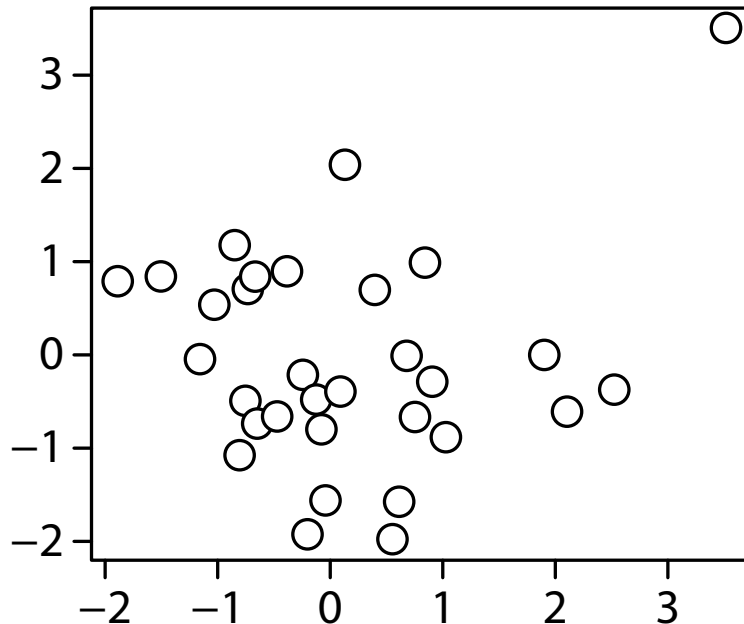


LOF is Popular

- LOF is one of the most popular outlier detection methods
 - Easy to use (only one parameter k)
 - Higher detection ability than k th-NN
- For example, a ML library **Jubatus** (<http://jubat.us/en/>) supports LOF as an outlier detection technique
- The main drawback: **scalability**
 - $O(n^2)$ is needed for neighbor search
 - Same as k th-NN

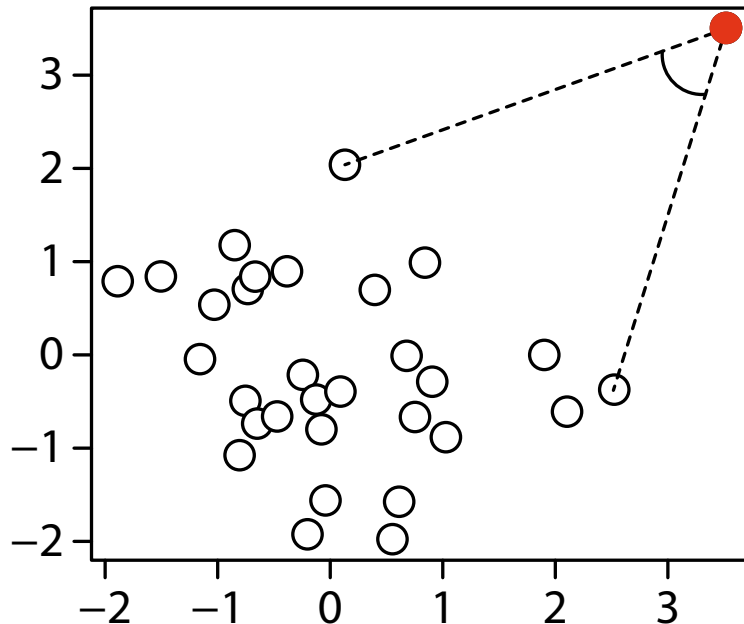
ABOD (Angle-Based Outlier Detection)

- If x is an outlier, the **variance of angles** between pairs of the remaining objects becomes small



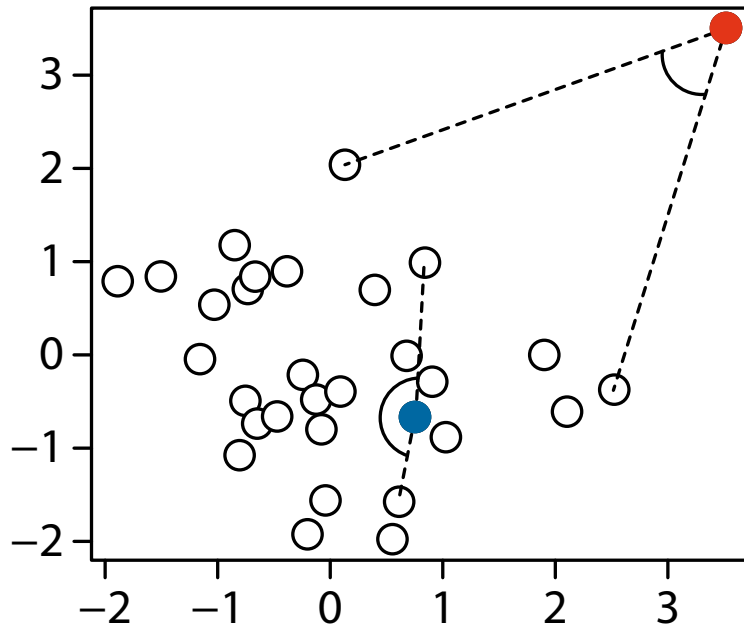
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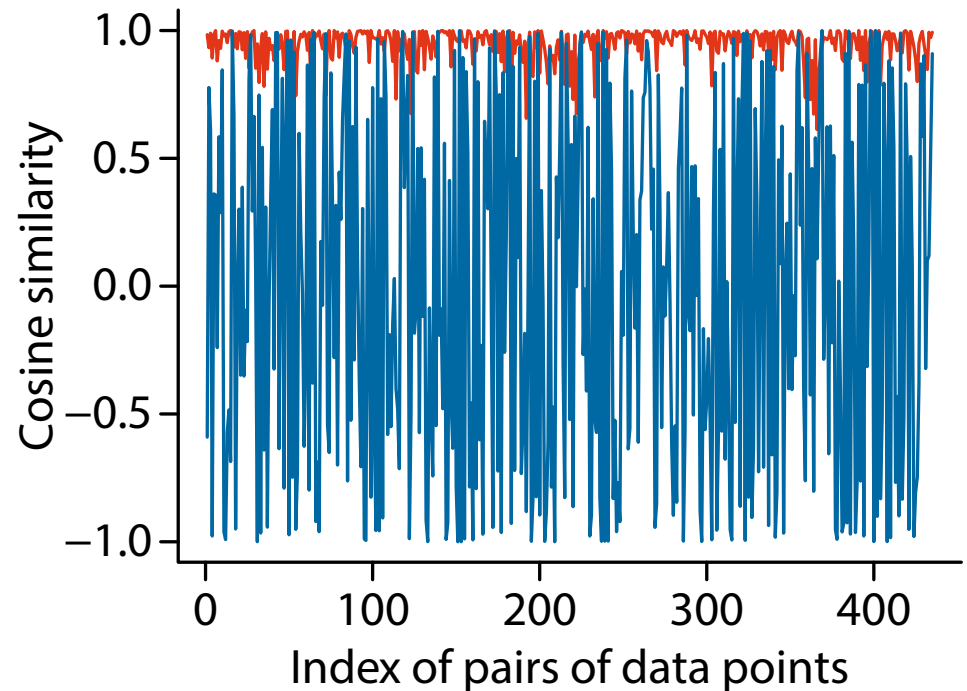
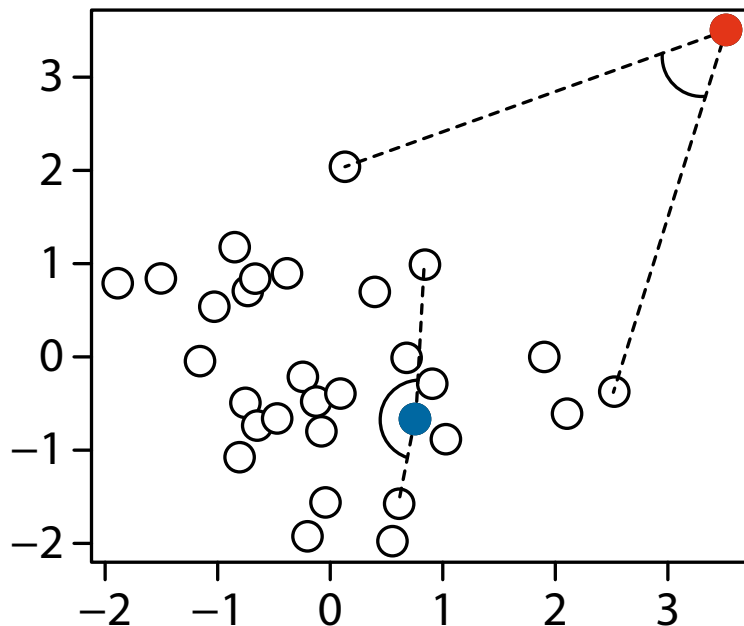
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Definition of ABOD

- If x is an outlier, the **variance of angles** between pairs of the remaining objects becomes small
- The score $ABOF(x) := \text{Var}_{y,z \in X} s(y - x, z - x)$
 - $s(x, y)$ is the **similarity** between vectors x and y , for example, the cosine similarity
 - $s(z - x, y - x)$ correlates with the **angle** of y and z w.r.t. the coordinate origin x
- Pros: Parameter-free
- Cons: High computational cost $O(n^3)$

Speeding Up ABOD

- Pham and Pagh proposed a speeded-up approximation algorithm **FastVOA**
 - Pham, N., Pagh, R., “A near-linear time approximation algorithm for angle-based outlier detection in high-dimensional data”, SIGKDD 2012
 - It estimates the first and the second moment of the variance $\text{Var}_{y,z \in X} s(y - x, z - x)$ independently using **random projections** and **AMS sketches**
- Pros: near-linear complexity: $O(tn(m + \log n + c_1 c_2))$
 - t : the number of hyperplanes for random projections
 - c_1, c_2 : the number of repetitions for AMS sketches
- Cons: Many parameters

Other Interesting Approaches

- **iForest** (isolation forest)
 - Liu, F.T. and Ting, K.M. and Zhou, Z.H., “Isolation forest”, ICDM 2008 (Best Paper Runner-Up)
 - A random forest-like method with recursive partitioning of datasets
 - An outlier tends to be easily partitioned
- **One-class SVM**
 - Schölkopf, B. et al., “Estimating the support of a high-dimensional distribution”, Neural computation (2001)
 - This classifies objects into inliers and outliers by introducing a hyperplane between them
 - This can be used as a ranking method by considering the signed distance to the separating hyperplane

iForest (Isolation Forest)

- Given X , we construct an *iTree*:
 1. A sample set $S(X) \subset X$ is chosen
 2. $S(X)$ is partitioned into $S(X)_L$ and $S(X)_R$ such that:
 $S(X)_L = \{x \in S(X) \mid x_q < v\}$, $S(X)_R = S(X) \setminus S(X)_L$,
where v and q are randomly chosen
 3. Recursively apply to each set until it becomes a singleton
- The outlierness score $iTree(x)$ is defined as $2^{-\overline{h(x)}/c(\mu)}$
 - $h(x)$ is the number of edges from the root to the leaf of x
 - $\overline{h(x)}$ is the average of $h(x)$ on t *iTrees*
 - $c(\mu) := 2H(\mu - 1) - 2(\mu - 1)/n$ (H is the harmonic number)

One-class SVM

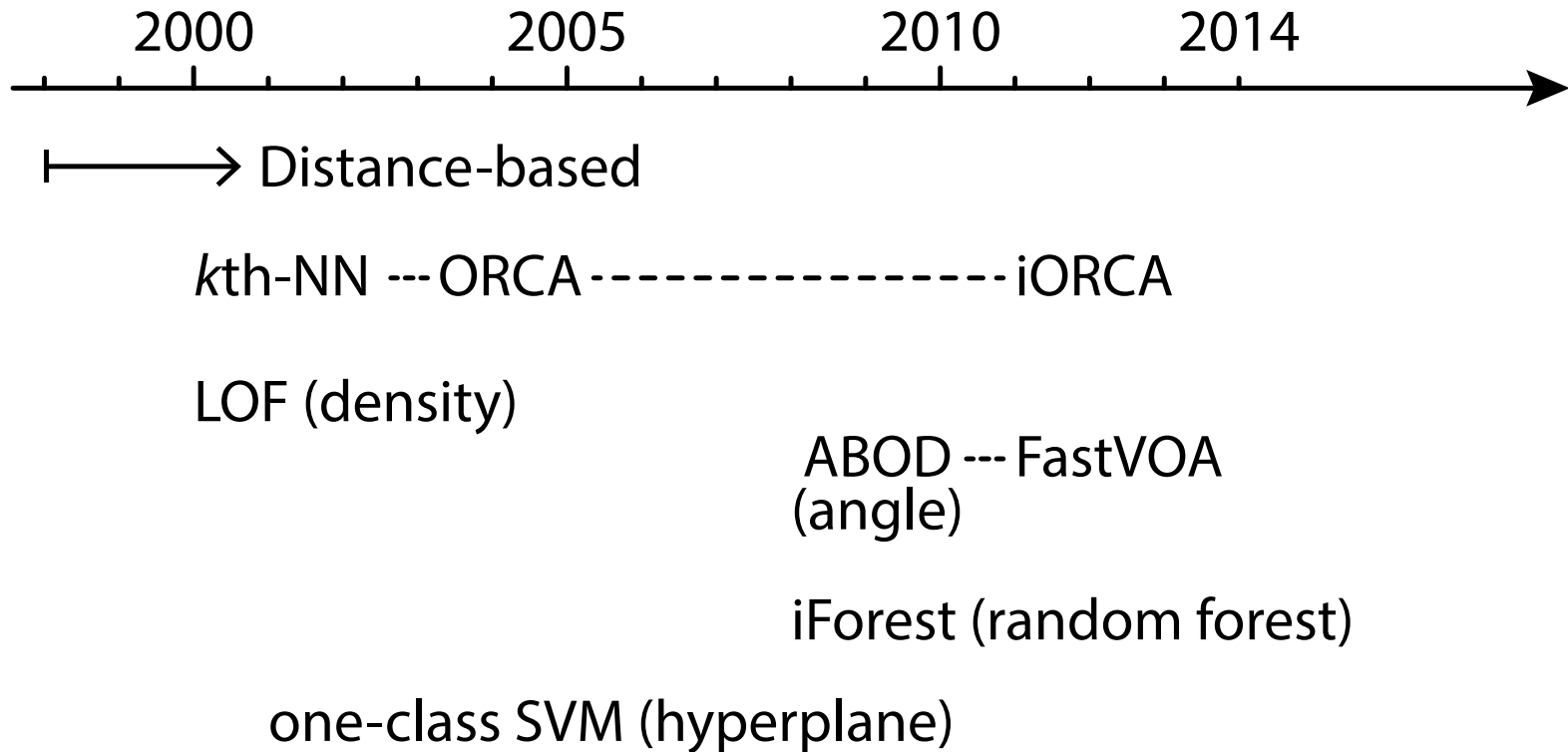
- A technique via hyperplanes by Schölkopf *et al.*
- The score of a vector \mathbf{x} is $\rho - (w \cdot \Phi(\mathbf{x}))$
 - Φ : a feature map
 - w and ρ are the solution of the following quadratic program:

$$\min_{w \in F, \xi \in \mathbb{R}^n, \rho \in \mathbb{R}} \frac{1}{2} \|w\|^2 + \frac{1}{vn} \sum_{i=1}^n \xi_i - \rho$$

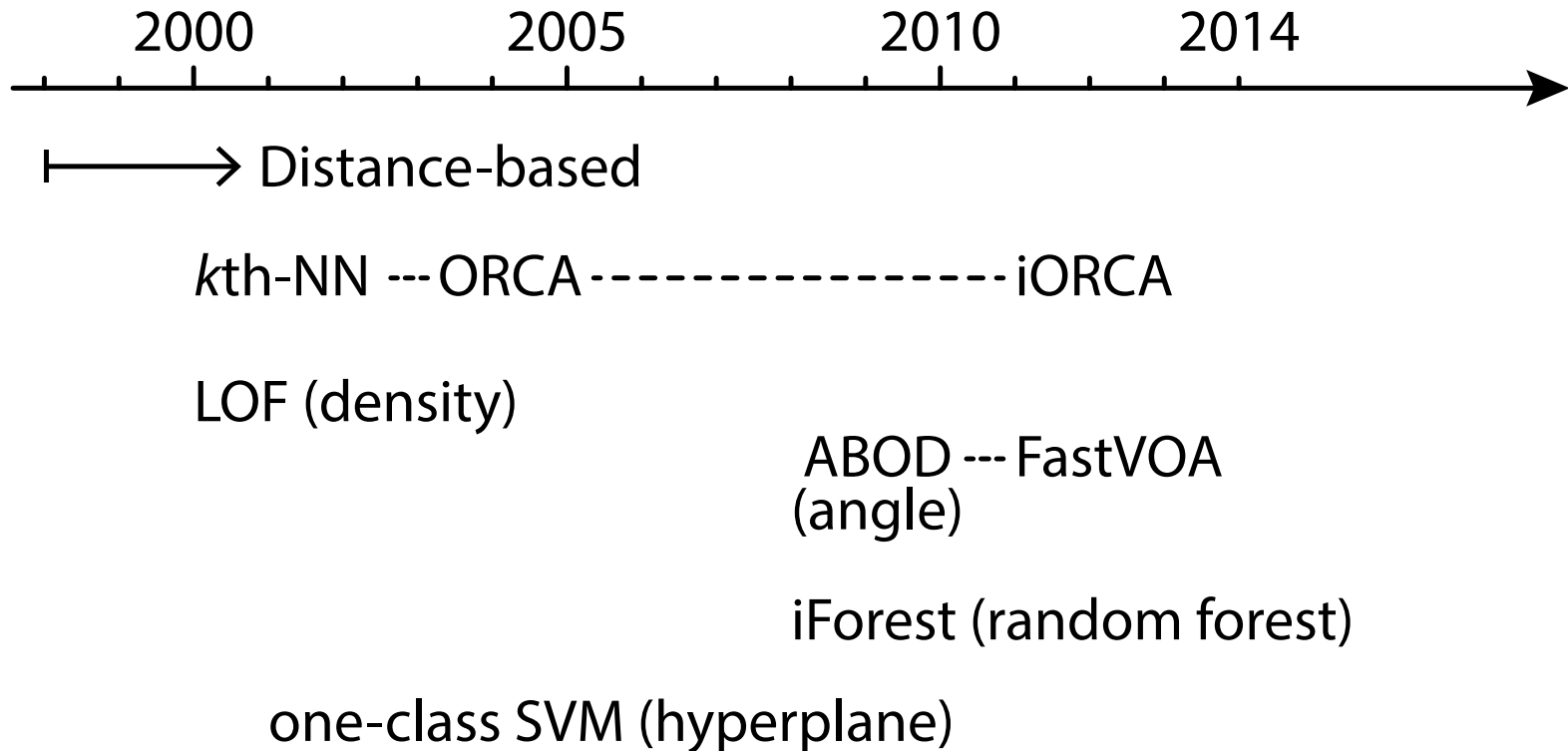
subject to $(w \cdot \Phi(x_i)) \geq \rho - \xi_i, \xi_i \geq 0$

- The term $w \cdot \Phi(\mathbf{x})$ can be replaced with $\sum_{i=1}^n a_i k(\mathbf{x}_i, \mathbf{x})$ using a kernel function k

Timeline

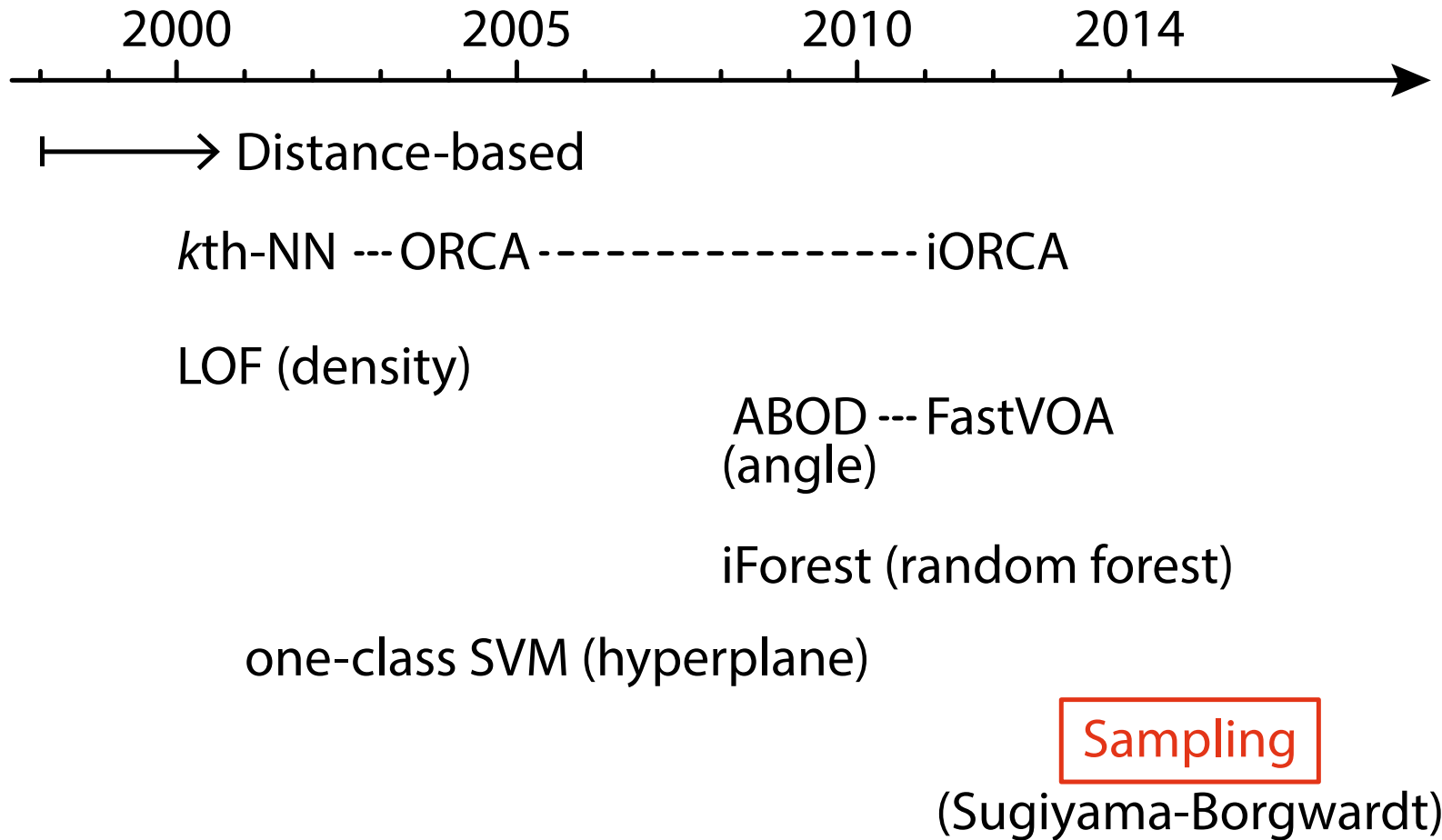


Timeline



The common drawback: **Scalability**

Timeline



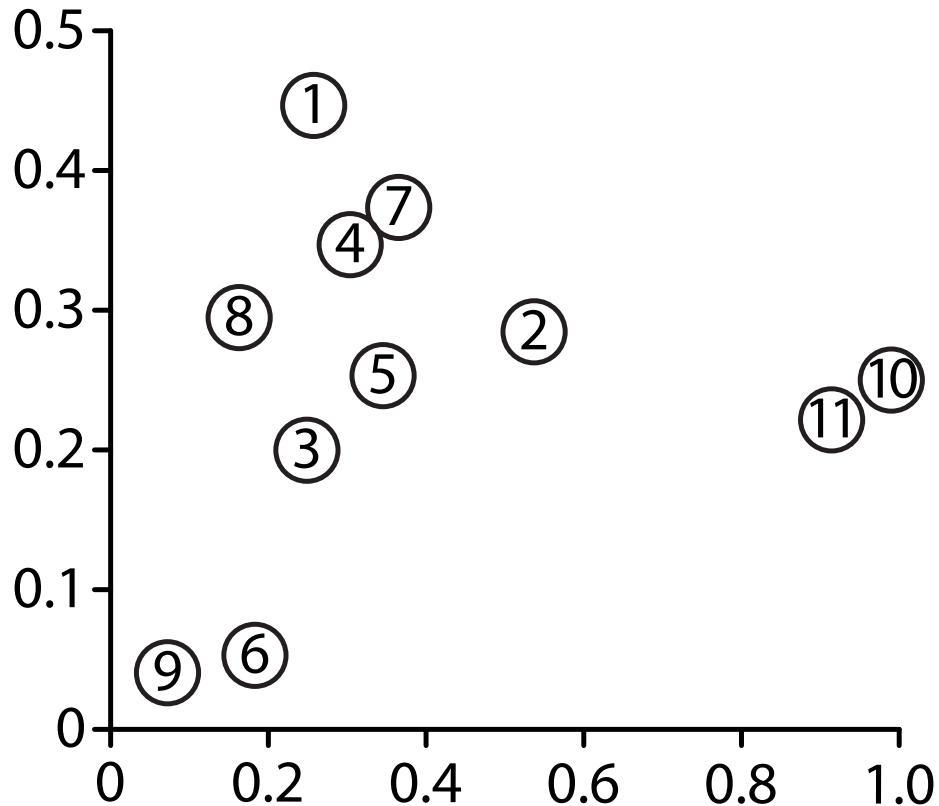
Sampling-Based Outlier Detection

- (Sub-)Sampling was largely ignored in outlier detection
 - Find outliers from samples seems hopeless
- We proposed to use samples as a reference set
 - Sugiyama, M., Borgwardt, K.M., “Rapid Distance-Based Outlier Detection via Sampling”, NIPS 2013
 - Sample size is surprisingly small, which is sometimes 0.0001% of the total number of data points
 - Accuracy is competitive with state-of-the-art methods

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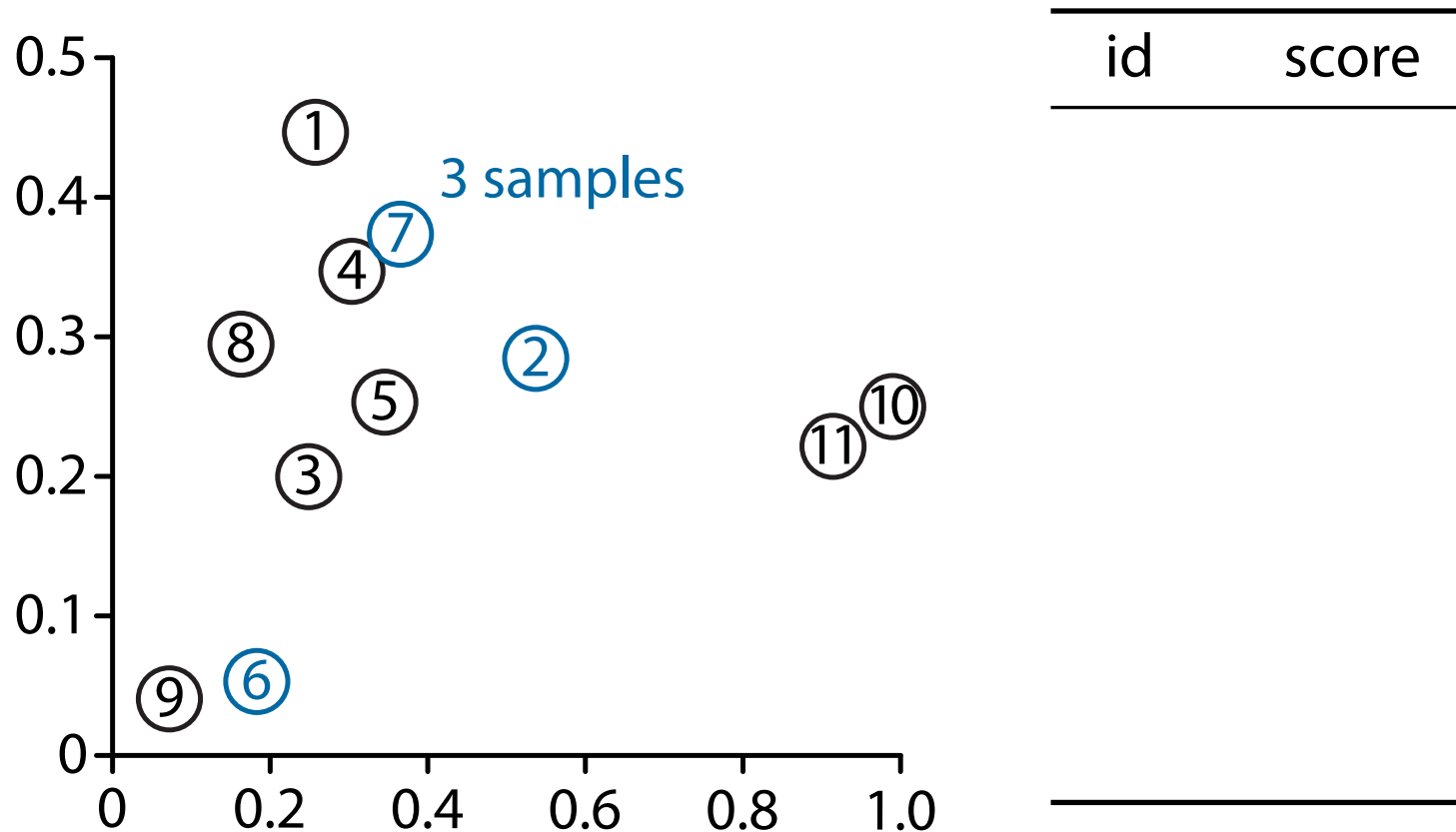
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 - Sample size is surprisingly small, which is sometimes 0.0001% of the total number of data points
 - Accuracy is competitive with state-of-the-art methods
- Ensemble method with subsampling was also proposed:
 - Zimek, A. et al., “Subsampling for Efficient and Effective Unsupervised Outlier Detection Ensembles”, SIGKDD 2013
 - Our method is more aggressive and direct

Sugiyama-Borgwardt Method

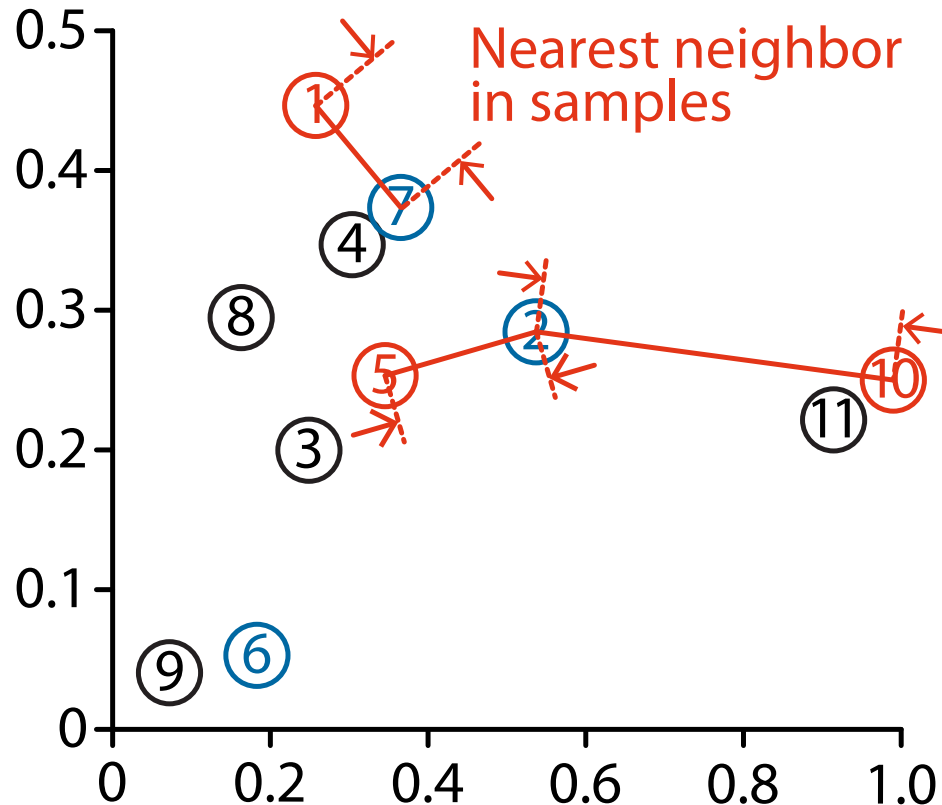


id	score
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Sugiyama-Borgwardt Method

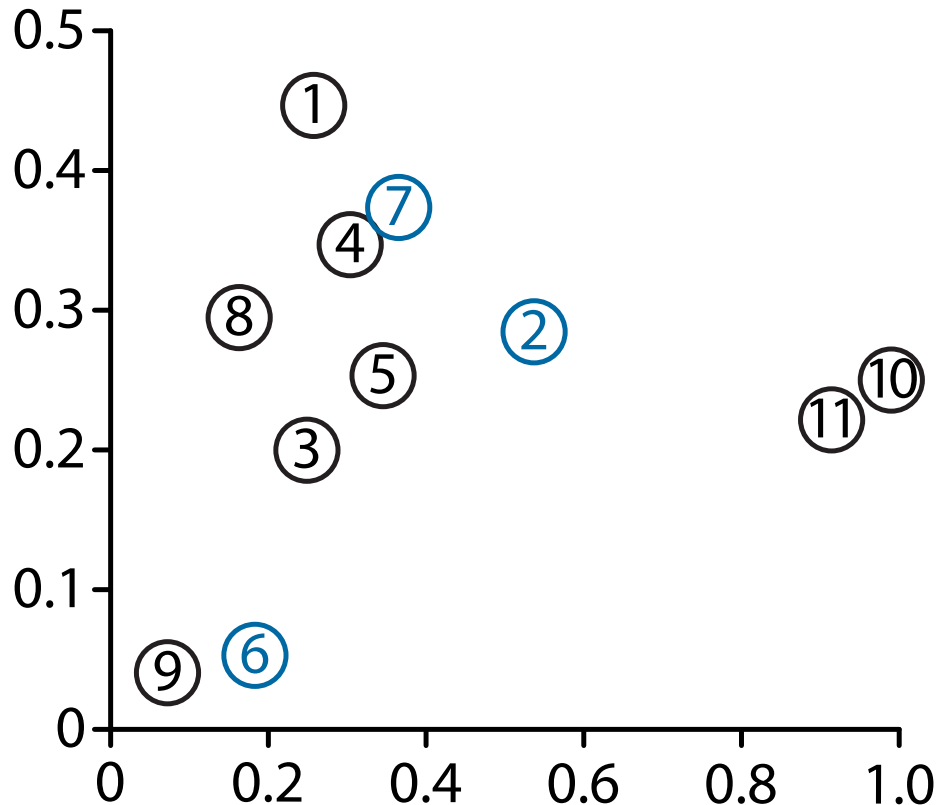


Sugiyama-Borgwardt Method



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1	0.130
5	0.122

Sugiyama-Borgwardt Method



id	score
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11	0.436
6	0.369
8	0.217
2	0.193
7	0.193
3	0.161
1	0.130
5	0.122
9	0.112
4	0.067

Definition

- Given a dataset X (n data points, m dimensions)
- Randomly and independently sample a subset $S(X) \subset X$
- Define the score $q_{sp}(x)$ for each object $x \in X$ as

$$q_{sp}(x) := \min_{x' \in S(X)} d(x, x')$$

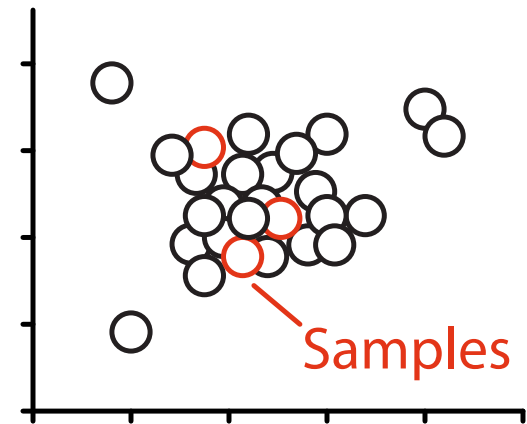
- Input parameter: the number of samples $s = |S(X)|$
- The time complexity is $\Theta(nms)$ and the space complexity is $\Theta(ms)$

Intuition

- Outliers should be significantly different from **almost all** inliers
 - A sample set includes only inliers with high probability
 - Outliers get high scores
- For each inlier, **at least** one similar data point is included in the sample set with high probability

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 - Outliers get high scores
- For each inlier, **at least** one similar data point is included in the sample set with high probability
- This scheme is expected to work with small sample sizes
 - If we pick up too many samples, some rare points, which is similar to an outlier, slip into the sample set



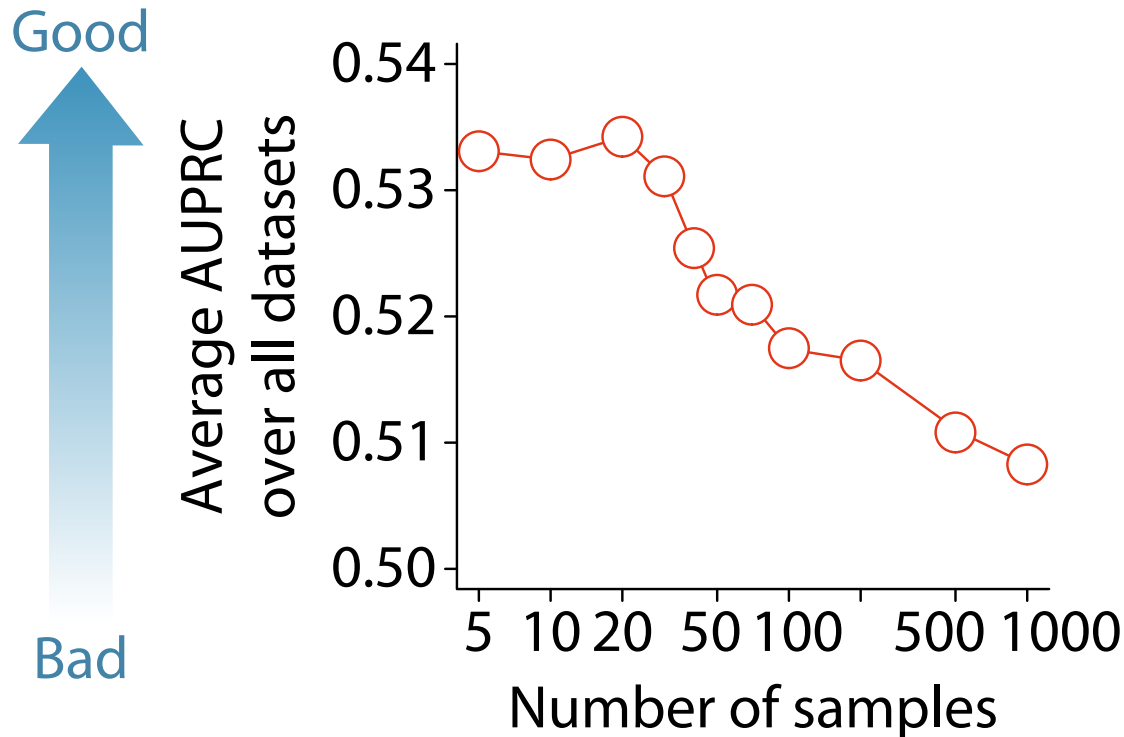
Experiments

- Examine state-of-the-art methods using synthetic and real-world datasets
 - Real data were collected from UCI repository
 - Points in the smallest class was assumed to be outliers
- Comparison partners:
 - *k*th-NN (iORCA), LOF, ABOD (FastVOA), iForest, one-class SVM, Wu and Jermaine's method
- Effectiveness was measured by **AUPRC** (area under the precision-recall curve)
 - Equivalent to the **average precision** over all possible cut-offs on the ranking of outlieriness

Datasets (* are synthetic)

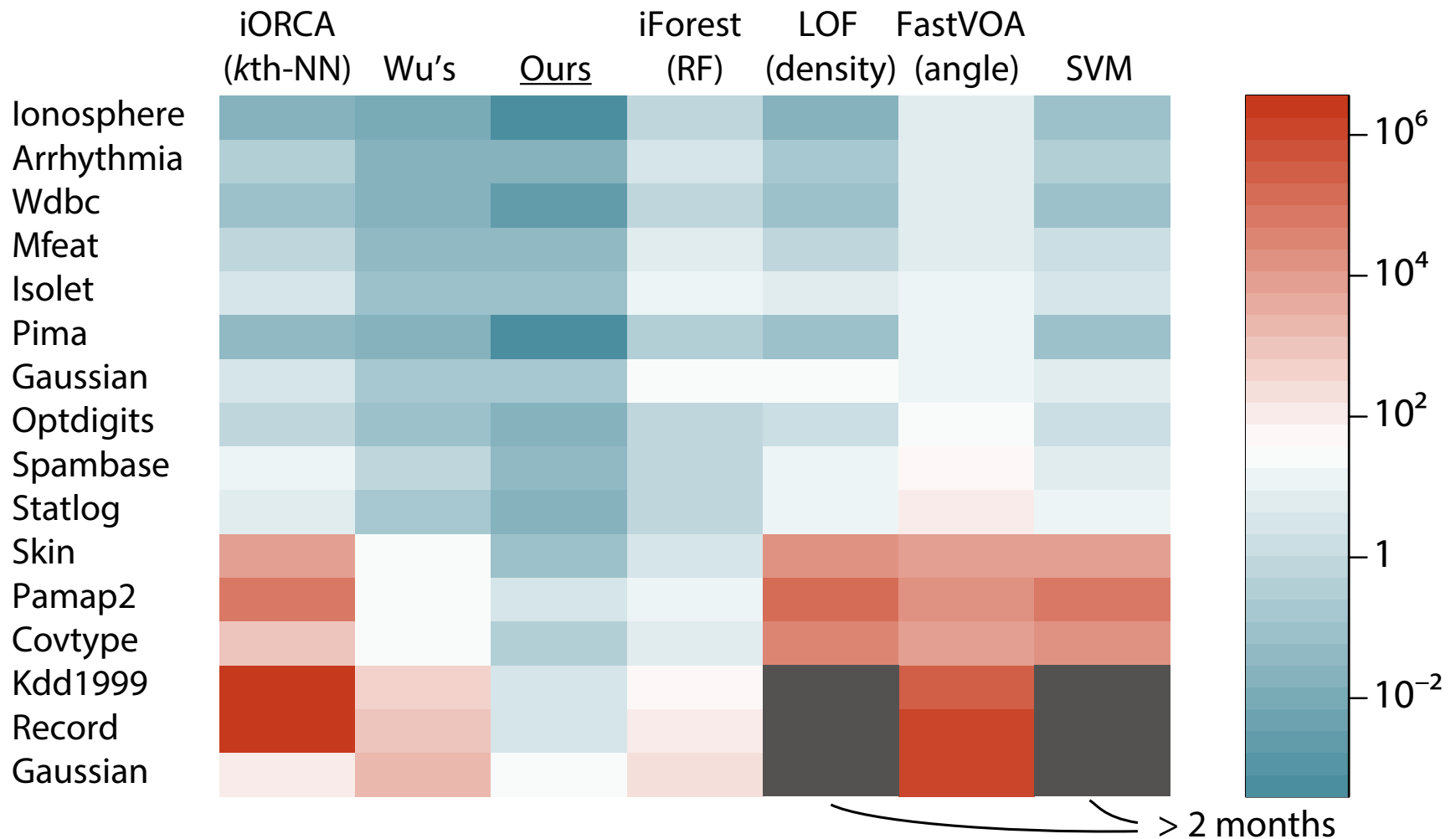
	# of objects	# of outliers	# of dims
Ionosphere	351	126	34
Arrhythmia	452	207	274
Wdbc	569	212	30
Mfeat	600	200	649
Isolet	960	240	617
Pima	768	268	8
Gaussian*	1000	30	1000
Optdigits	1688	554	64
Spambase	4601	1813	57
Statlog	6435	626	36
Skin	245057	50859	3
Pamap2	373161	125953	51
Covtype	286048	2747	10
Kdd1999	4898431	703067	6
Record	5734488	20887	7
Gaussian*	10000000	30	20

Sensitivity in sample sizes

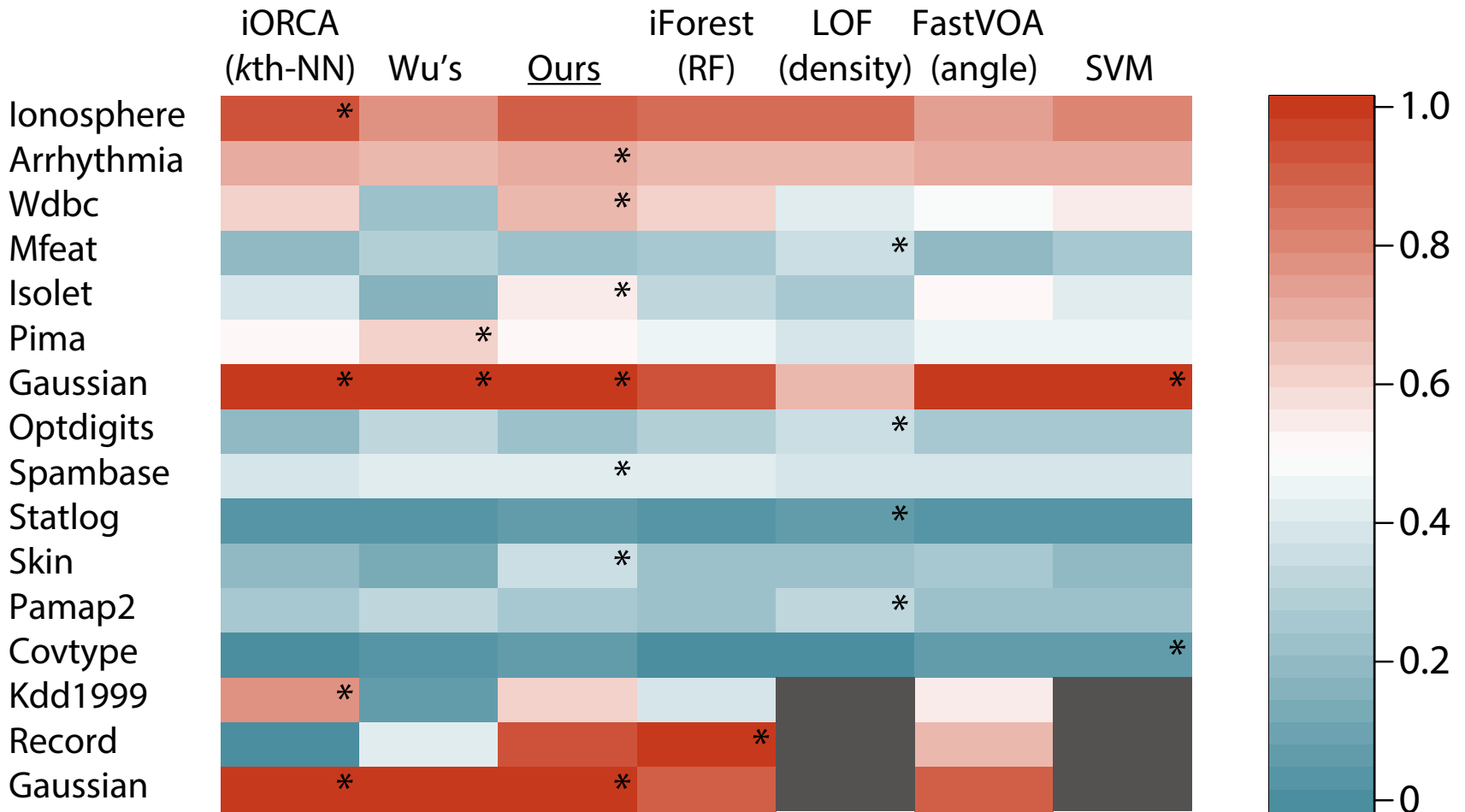


- Interestingly, the effectiveness was maximized at a rather small sample size, 20
 - Monotonically decreased as the sample size increased further

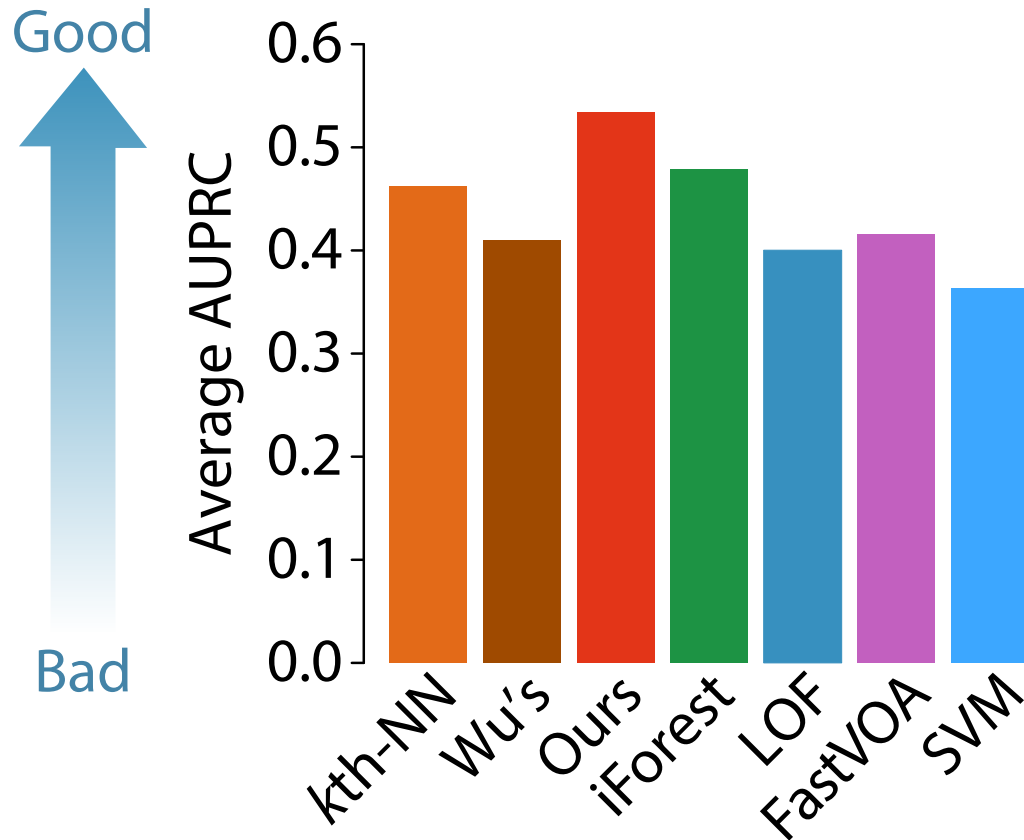
Running Time (seconds)



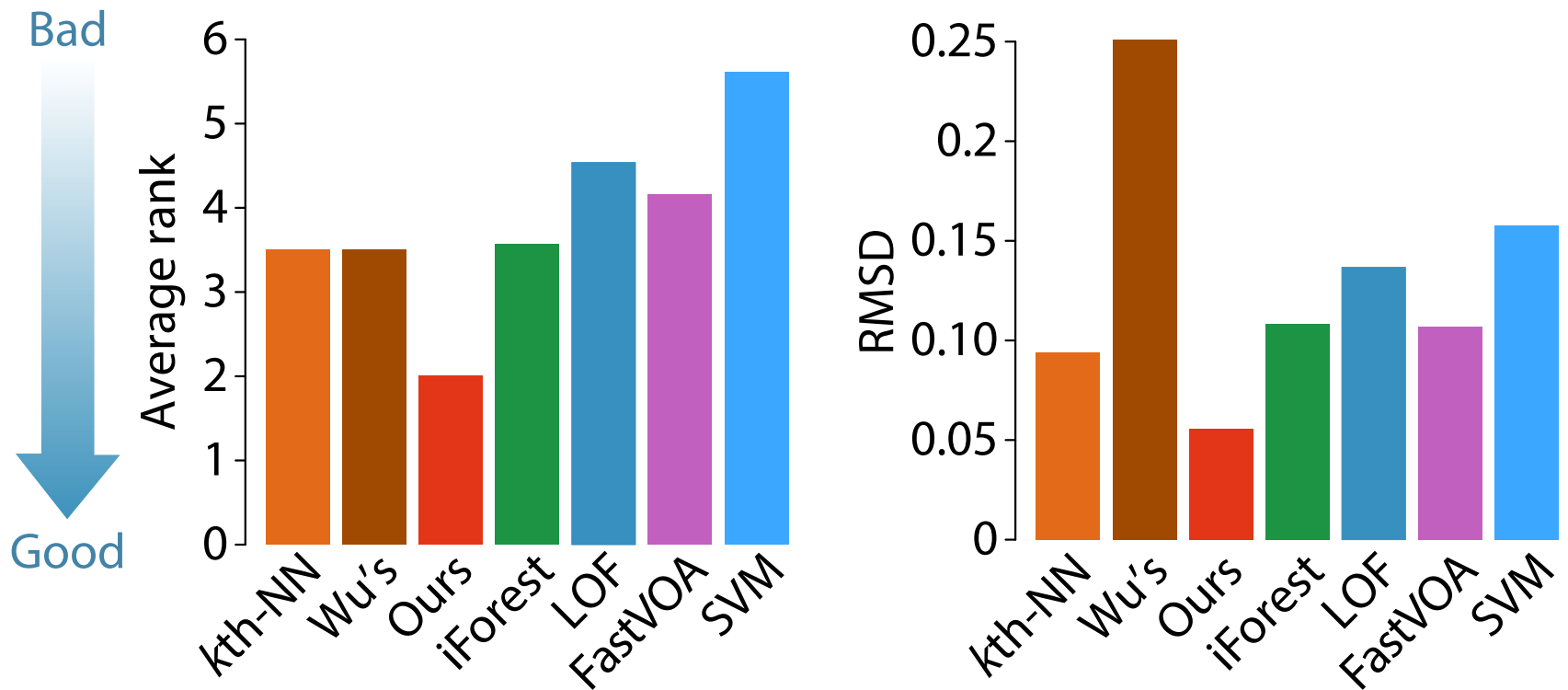
AUPRC (* are best scores)



Average of AUPRC over all datasets



Other statistics



- RMSD: the root-mean-square deviation to the best scores, rewarding methods that are always close to the best result

Notations

- $X(\alpha; \delta)$: the set of Knorr and Ng's DB(α, δ)-outliers
- $x \in X(\alpha; \delta)$ if $|\{x' \in X \mid d(x, x') > \delta\}| \geq \alpha n$
 - $\bar{X}(\alpha; \delta) = X \setminus X(\alpha; \delta)$: the set of inliers
 - α is expected to close to 1, meaning that an outlier is distant from almost all points
- Define β ($0 \leq \beta \leq \alpha$) as the minimum value s.t.
$$\forall x \in \bar{X}(\alpha; \delta), \left| \{x' \in X \mid d(x, x') > \delta\} \right| \leq \beta n$$

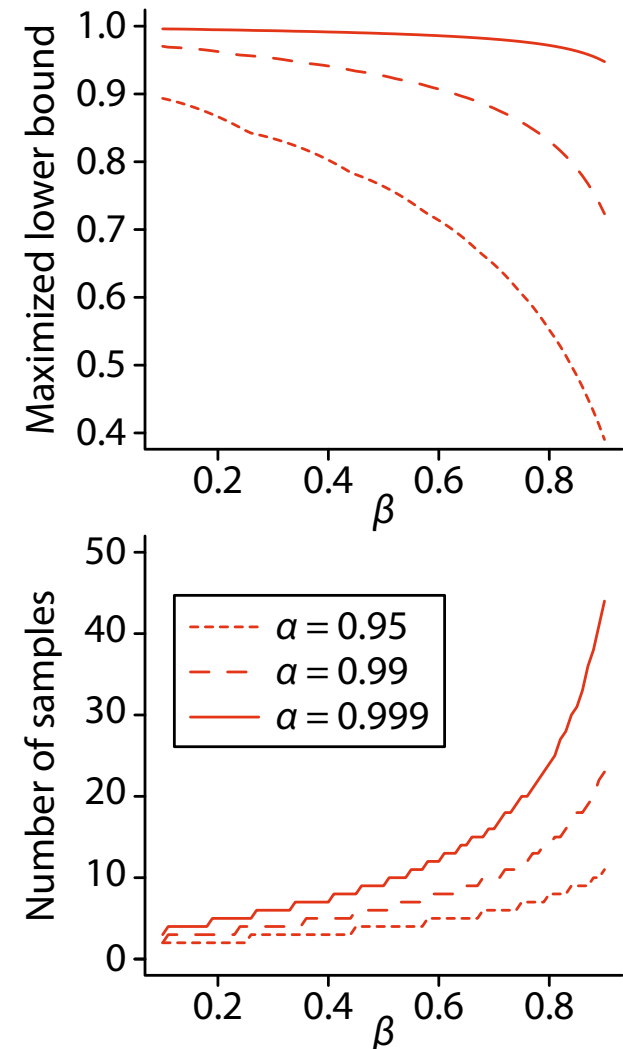
Theoretical Results

1. For $x \in X(\alpha; \delta)$ and $x' \in \bar{X}(\alpha; \delta)$,
 $\Pr(q_{\text{sp}}(x) > q_{\text{sp}}(x')) \geq \alpha^s (1 - \beta^s)$
(s is the number of samples)
 - This lower bound tends to be high in a typical setting (α is large, β is moderate)

2. This bound is maximized at

$$s = \log_{\beta} \frac{\log \alpha}{\log \alpha + \log \beta}$$

- This value tends to be small

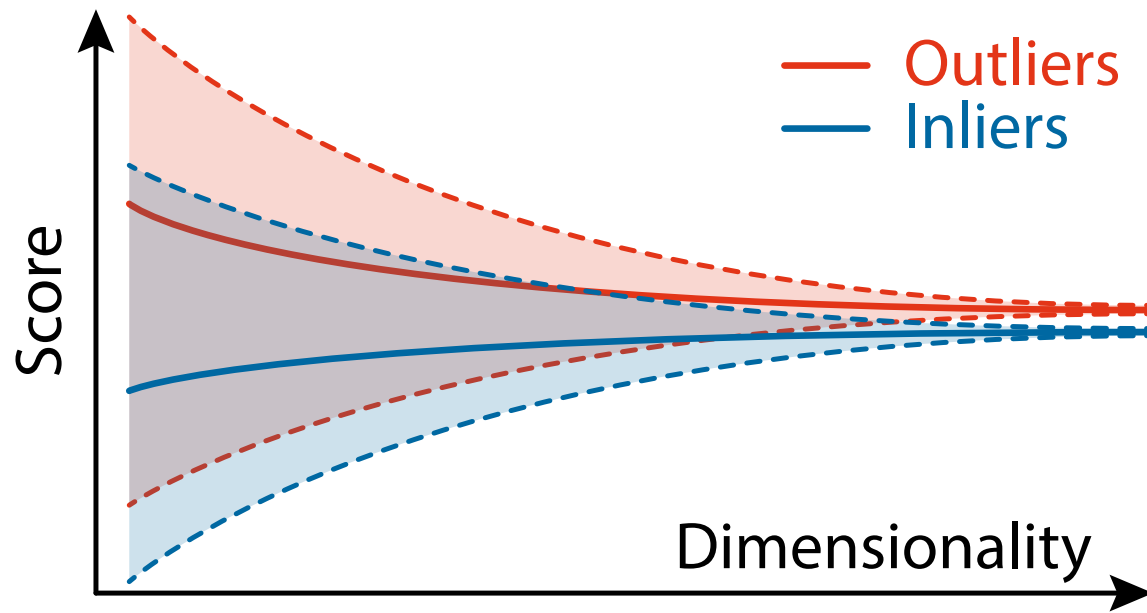


How about High-dimensional Data ?

- So-called “the curse of dimensionality”
- There is an interesting paper that studies outlier detection in high-dimensional data
 - Zimek, A., Schubert, E., Kriegel, H.-P., “A survey on unsupervised outlier detection in high-dimensional numerical data”, Statistical Analysis and Data Mining (2012)

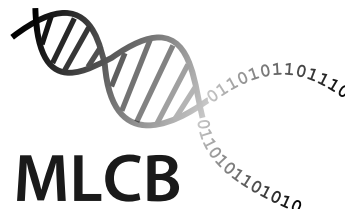
Fact about High-Dimensional Data

- High-dimensionality is **not** always the problem
 - If all attributes are relevant, detecting outliers becomes easier and easier as attributes (dimensions) increases
 - Of course, it is not the case if irrelevant attributes exist



Conclusion

- **Sampling** is a powerful tool in outlier detection
- Sugiyama-Borgwardt method is
 - much (2 to 6 orders of magnitude) faster than exhaustive methods
 - **the most effective** on average
- Future work:
 - On-line outlier detection with updating samples
 - Apply to other data types
- Thanks to:



Unterstützt von / Supported by



Evaluation criteria

- Precision v.s. Recall (Sensitivity)
 - $\text{Recall} = \text{TP} / (\text{TP} + \text{FN})$
 - $\text{Precision} = \text{TP} / (\text{TP} + \text{FP})$
- cf. ROC curve: False Positive Rate (FPR) v.s. Sensitivity
 - $\text{FPR} = \text{FP} / (\text{FP} + \text{TN}) = 1 - \text{Specificity}$
 - $\text{Sensitivity} = \text{TP} / (\text{TP} + \text{FN})$

Relationship

	Ground truth		
	Condition Positive	Condition Negative	
Test Outcome Positive	True Positive	False Positive (Type I Error)	Precision $TP / (TP + FP)$
Test Outcome Negative	False Negative (Type II Error)	True Negative	
	Sensitivity (Recall) $TP / (TP + FN)$	Specificity $TN / (FP + TN) = 1 - FPR$ False Positive Rate (FPR) $FP / (FP + TN)$	

Wu and Jermaine's method

- Define the score of x as $d^k(x; S_x(X))$
 - $d^k(x; X)$ is the distance between x and its k th-NN in X
 - $S_x(X)$ is a subset of X , which is randomly and iteratively sampled for each object x
- Closely related to our method when $k = 1$
 - our method performs sampling only once
 - Wu's method performs sampling per each object

More Detailed Analysis

- A δ -partition \mathcal{P}_δ of $\bar{X}(\alpha; \delta)$:
 $\forall C \in \mathcal{P}_\delta, \max_{x,y \in C} d(x,y) < \delta$ and $\bigcup_{C \in \mathcal{P}_\delta} C = \bar{X}(\alpha; \delta)$
- For an outlier $x \in X(\alpha; \delta)$ and a cluster $C \in \mathcal{P}_\delta$,
 $\Pr(\forall x' \in C, q_{\text{sp}}(x) > q_{\text{sp}}(x')) \geq \alpha^s (1 - \beta^s)$ with $\beta = (n - |C|)/n$
- Let $I(\alpha; \delta) \subset \bar{X}(\alpha; \delta)$ s.t. $\forall x \in X(\alpha; \delta), \min_{x' \in I(\alpha; \delta)} d(x, x') > \delta$, $\mathcal{P}_\delta = \{C_1, \dots, C_l\}$ be a δ -partition of $I(\alpha; \delta)$, and $p_i = |C_i|/|I(\alpha; \delta)|$ for each $i \in \{1, \dots, l\}$
- Let $\varphi(s) = \sum_{\forall i; s_i \geq 0} f(s_1, \dots, s_l; \mu, p_1, \dots, p_l)$, where f is the probability mass function of the multinomial distribution, and $\gamma = |I(\alpha; \delta)|/n$. Then

$$\Pr(\forall x \in X(\alpha; \delta), \forall x' \in \bar{X}(\alpha; \delta), q_{\text{sp}}(x) > q_{\text{sp}}(x')) \geq \gamma^s \max_{\mathcal{P}_\delta} \varphi(s)$$